Application/Control No. 10/699,664 Examiner Tu M. Nguyen Applicant(s)/Patent Under Reexamination MINAMI, TOSHITAKA Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2006/0242947	11-2006	Kay et al.	060/284
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